

<b>Notice of References Cited</b>	Application/Control No. 10/715,376	Applicant(s)/Patent Under Reexamination SUN ET AL.	
	Examiner Thinh T. Nguyen	Art Unit 2818	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,917,749	06-1999	Chen et al.	365/173
*	C	US-6,341,053	01-2002	Nakada et al.	360/324.2
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**NON-PATENT DOCUMENTS**

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